

General Description

The BSC037N08NS5 use advanced SGT MOSFET technology to provide low RDS(ON), low gate charge, fast switching and excellent avalanche characteristics.

This device is specially designed to get better ruggedness and suitable.

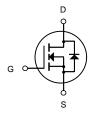


DFN5X6-8L

General Features

V_{DS} =85V I_D =100A

 $R_{DS(ON)} < 5.6m\Omega@V_{GS}=10V$



N-Channel MOSFET

Applications

Consumer electronic power supply Motor control

Synchronous-rectification Isolated DC

Synchronous-rectification applications

Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)
BSC037N08NS5	DFN5X6-8L	HXY MOSFET	5000

Absolute Maximum Ratings (T_C=25[°]Cunless otherwise noted)

Symbol	Parameter	Rating	Units
V _D s	Drain-Source Voltage	85	V
Vgs	Gate-Source Voltage	±20	V
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ 10V	100	А
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ 10V	63.3	А
Ірм	Pulsed Drain Current ²	400	А
EAS	Single Pulse Avalanche Energy ³	273.8	mJ
P _D @T _C =25°C	Total Power Dissipation ⁴	107.8	W
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
R₀Jc	Thermal Resistance from Junction-to-Ambient ³	1.16	°C/W
Reja	Thermal Resistance Junction-Ambient ¹	60	°C/W



Electrical Characteristics (T_J = 25°C, unless otherwise noted)

Parameter		Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static Characteristics							
Drain-Source Breakdown Voltage		V _{(BR)DSS}	V _{GS} = 0V, I _D = 250µA	85	-	-	V
Gate-body Leakage current		Igss	V _{DS} = 0V, V _{GS} = ±20V	-	-	±100	nA
Zero Gate Voltage Drain Current	TJ=25℃		V _{DS} = 85V, V _{GS} = 0V	-	-	1	μА
	TJ=100℃	I _{DSS}		-	-	100	
Gate-Threshold Voltage		V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250μA	2	3	4	V
Drain-Source on-Resistance ⁴		R _{DS(on)}	V _{GS} = 10V, I _D = 20A	-	4.3	5.6	mΩ
Forward Transconductance ⁴		G fs	V _{DS} = 5V, I _D =20A	-	57.8	-	S
Dynamic Characteristic	S ⁵						
Input Capacitance		C _{iss}		-	4645	-	pF
Output Capacitance		Coss	V _{DS} = 40V, V _{GS} =0V, f =1MHz	-	673	-	
Reverse Transfer Capacitance		Crss		-	41	-	
Gate Resistance		Rg	f=1MHz	-	2.0	-	Ω
Switching Characteristi	CS ⁵						
Total Gate Charge		Qg	V _{GS} = 10V, V _{DS} = 40V, I _D = 20A	-	61.3	-	nC
Gate-Source Charge		Qgs		-	21	-	
Gate-Drain Charge		Q _{gd}		-	11	-	
Turn-on Delay Time		t _{d(on)}		-	16.5	-	ns ns
Rise Time		tr	$V_{GS} = 10V, V_{DD} = 40V,$ $R_{G} = 3\Omega, I_{D} = 20A$	-	51.8	-	
Turn-off Delay Time		t _{d(off)}		-	37.1	-	
Fall Time		tf		-	8.2	-	
Body Diode Reverse Recovery Time		t _{rr}		-	69	-	ns
Body Diode Reverse Recovery Charge		Qrr	- I _F =20A, di/dt = 100A/μS	-	141	-	nC
Drain-Source Body Dio	de Characte	eristics	•	•			
Diode Forward Voltage ⁴		V _{SD}	Is = 20A, V _{GS} = 0V	-	_	1.2	V
Continuous Source Current T _C =25℃		Is	-	-	-	100	Α

Notes:

- 1. Repetitive rating, pulse width limited by junction temperature $TJ(MAX)=150^{\circ}C$
- 2. The EAS data shows Max. rating . The test condition is V_{DD} =50V, V_{GS} =10V, L=0.4mH, I_{AS} =37A
- 3. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper, The value in any given application depends on the user's specific board design.
- 4. The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%.
- 5. This value is guaranteed by design hence it is not included in the production test.



Typical Characteristics

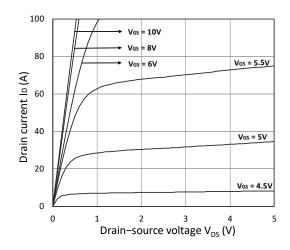


Figure 1. Output Characteristics

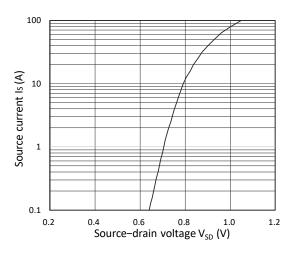


Figure 3. Forward Characteristics of Reverse

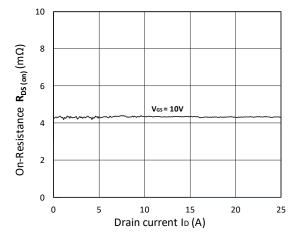


Figure 5. $R_{\rm DS(ON)}$ vs. $I_{\rm D}$

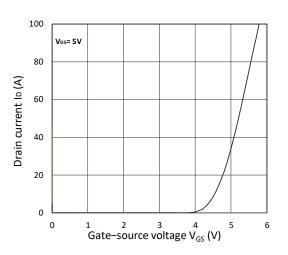


Figure 2. Transfer Characteristics

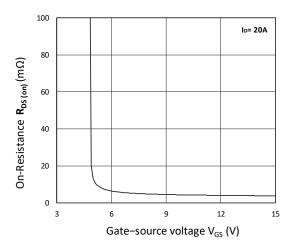


Figure 4. $R_{\text{DS}(\text{ON})}\,$ vs. $V_{\text{GS}}\,$

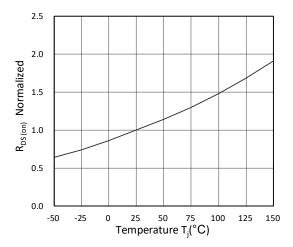


Figure 6. Normalized $R_{\text{DS(on)}}$ vs. Temperature

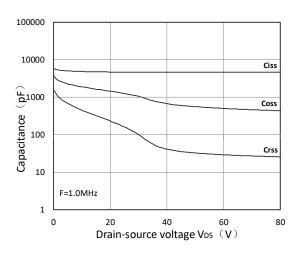
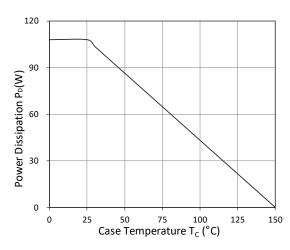


Figure 7. Capacitance Characteristics





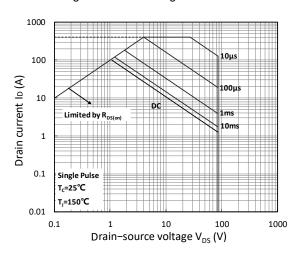


Figure 9. Power Dissipation

Figure 10. Safe Operating Area

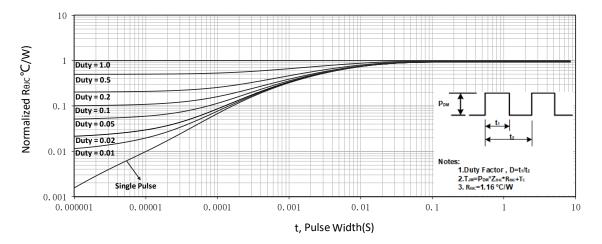
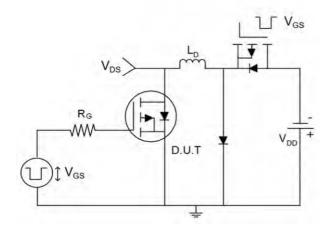
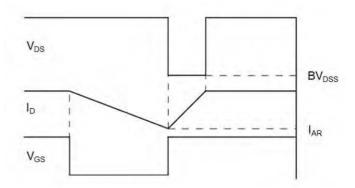


Figure 11. Normalized Maximum Transient Thermal Impedance

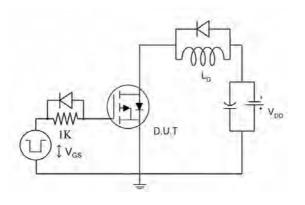


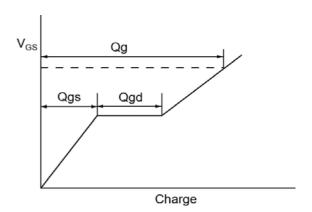
1) E_{AS} Test Circuits



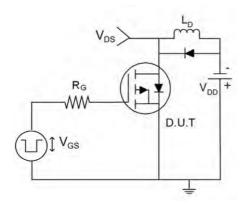


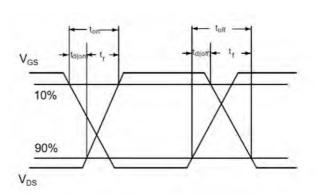
2) Gate Charge Test Circuit





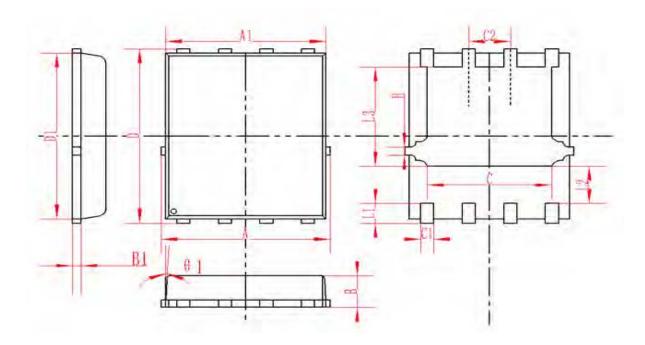
3) Switch Time Test Circuit







DFN5X6-8L Package Information



SYMBOL	MM			INCH		
	MIN	NOM	MAX	MIN	NOM	MAX
А	4.95	5	5.05	0.195	0.197	0.199
A1	4.82	4.9	4.98	0.190	0.193	0.196
D	5.98	6	6.02	0.235	0.236	0.237
D1	5.67	5.75	5.83	0.223	0.226	0.230
В	0.9	0.95	1	0.035	0.037	0.039
B1	0.254REF		0.010REF			
С	3.95	4	4.05	0.156	0.157	0.159
C1	0.35	0.4	0.45	0.014	0.016	0.018
C2		1.27TYP			0.5TYP	
θ1	8°	10°	12°	8°	10°	12°
L1	0.63	0.64	0.65	0.025	0.025	0.026
L2	1.2	1.3	1.4	0.047	0.051	0.055
L3	3.415	3.42	3.425	0.134	0.135	0.135
Н	0.24	0.25	0.26	0.009	0.010	0.010



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